

Reconfigurable Field Programmable Gate Arrays for Mission-Critical Applications

Niccolò Battezzati · Luca Sterpone · Massimo Violante

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Niccolò Battezzati
Dipto. Automatica e Informatica
Politecnico di Torino
Corso Duca degli Abruzzi 24
10129 Torino, Italy
niccolo.battezzati@polito.it

Luca Sterpone
Politecnico di Torino
Corso Duca Degli Abruzzi 24
10129 Torino, Italy
luca.sterpone@polito.it

Massimo Violante
Dipto. Automatica e Informatica
Politecnico di Torino
Corso Duca degli Abruzzi 24
10129 Torino, Italy
massimo.violante@polito.it

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